

**IN THE CLAIMS**

1. (Currently Amended) A semiconductor device comprising:  
  
    ~~data~~ signal lines over which ~~signals~~ data are transferred; and  
  
    a drive circuit driving the ~~signal~~ data lines in operating modes, the operating modes including a dynamic operation mode in which the ~~signal~~ data lines are precharged prior to transfer of the ~~signals~~ data over said ~~signal~~ data lines, and a static operation mode in which the ~~signal~~ data lines are not precharged prior to transfer of the ~~signals~~ data over said signal lines.
  
2. (Original) The semiconductor device as claimed in claim 1, further comprising a memory cell array to which the ~~signal~~ data lines are connected, data read from the memory cell array being transferred over the ~~signal~~ data lines.
  
3. (Currently Amended) The semiconductor device as claimed in claim 1, further comprising a test-dedicated line,  
  
    a predetermined test of the semiconductor device being performed using the test-dedicated line and the ~~signal~~ data lines.
  
4. (Currently Amended) The semiconductor device as claimed in claim 3, further comprising a circuit receiving the ~~signal~~ data lines at inputs thereof and outputting a test result, said test result and a logic level of the test-dedicated line forming a result of the predetermined test.

5. (Currently Amended) The semiconductor device as claimed in claim 3, further comprising a precharge circuit precharging the ~~signal~~ data lines and the test-dedicated line.

6. (Currently Amended) The semiconductor device as claimed in claim 5, the precharge circuit precharging the ~~signal~~ data lines and the test-dedicated line in the dynamic operation mode only.